SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

- **Trimmed Offset Voltage: TLC279 . . . 900** μV Max at 25°C, $V_{DD} = 5 V$
- Input Offset Voltage Drift ... Typically 0.1 µV/Month, Including the First 30 Days
- Wide Range of Supply Voltages Over **Specified Temperature Range:** 0° C to 70° C . . . 3 V to 16 V -40°C to 85°C . . . 4 V to 16 V -55°C to 125°C . . . 4 V to 16 V
- Single-Supply Operation
- **Common-Mode Input Voltage Range Extends Below the Negative Rail (C-Suffix** and I-Suffix Versions)
- Low Noise . . . Typically 25 nV/ \sqrt{Hz} at f = 1 kHz
- **Output Voltage Range Includes Negative** Rail
- High Input Impedance . . . $10^{12} \Omega$ Typ
- **ESD-Protection Circuitry** •
- **Small-Outline Package Option Also** Available in Tape and Reel
- **Designed-In Latch-Up Immunity**

description

The TLC274 and TLC279 quad operational amplifiers combine a wide range of input offset voltage grades with low offset voltage drift, high input impedance, low noise, and speeds approaching that of general-purpose BiFET devices.

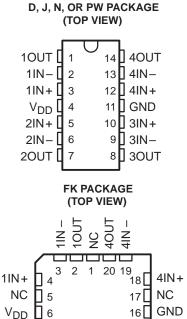
These devices use Texas Instruments silicon-gate LinCMOS™ technology, which provides offset voltage stability far exceeding the stability available with conventional metal-gate processes.

The extremely high input impedance, low bias currents, and high slew rates make these cost-effective devices ideal for applications which have previously been reserved for BiFET and NFET products. Four offset voltage grades are available (C-suffix and I-suffix types), ranging from the low-cost TLC274 (10 mV) to the highprecision TLC279 (900 µV). These advantages, in combination with good common-mode rejection and supply voltage rejection, make these devices a good choice for new state-of-the-art designs as well as for upgrading existing designs.

LinCMOS is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.







9 10 11 12 13

h

7

NC

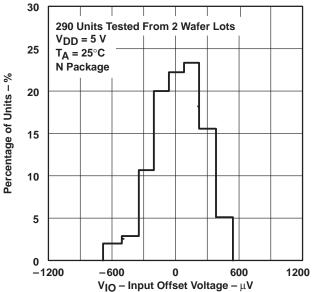
2IN+ П 8

DISTRIBUTION OF TLC279 INPUT OFFSET VOLTAGE

15 🗍 NC

3IN +

14



Copyright © 1998, Texas Instruments Incorporated

SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

description (continued)

In general, many features associated with bipolar technology are available on LinCMOS[™] operational amplifiers, without the power penalties of bipolar technology. General applications such as transducer interfacing, analog calculations, amplifier blocks, active filters, and signal buffering are easily designed with the TLC274 and TLC279. The devices also exhibit low voltage single-supply operation, making them ideally suited for remote and inaccessible battery-powered applications. The common-mode input voltage range includes the negative rail.

A wide range of packaging options is available, including small-outline and chip-carrier versions for high-density system applications.

The device inputs and outputs are designed to withstand –100-mA surge currents without sustaining latch-up.

The TLC274 and TLC279 incorporate internal ESD-protection circuits that prevent functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2; however, care should be exercised in handling these devices as exposure to ESD may result in the degradation of the device parametric performance.

The C-suffix devices are characterized for operation from 0°C to 70°C. The I-suffix devices are characterized for operation from -40°C to 85°C. The M-suffix devices are characterized for operation over the full military temperature range of -55°C to 125°C.

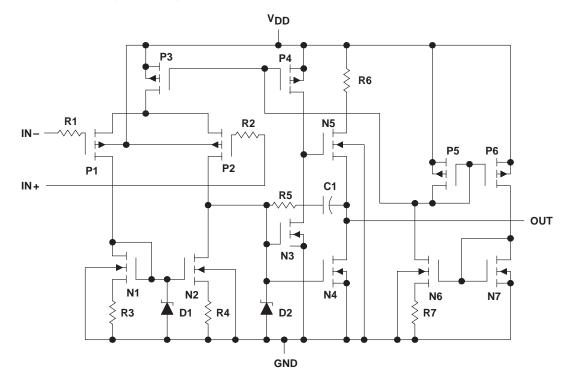
	· · · · · · · · · · · · · · · · · · ·	· · · · · · · · · · · · · · · · · · ·					
			PA	CKAGED DEV	ICES		CHIP
Τ _Α	V _{IO} max AT 25°C	SMALL OUTLINE (D)	CHIP CARRIER (FK)	CERAMIC DIP (J)	PLASTIC DIP (N)	TSSOP (PW)	FORM (Y)
0°C to 70°C	900 μV 2 mV 5 mV 10 mV	TLC279CD TLC274BCD TLC274ACD TLC274CD			TLC279CN TLC274BCN TLC274ACN TLC274CN	 TLC274CPW	— — — TLC274Y
-40°C to 85°C	900 μV 2 mV 5 mV 10 mV	TLC279ID TLC274BID TLC274AID TLC274AID			TLC279IN TLC274BIN TLC274AIN TLC274IN		
–55°C to 125°C	900 μV 10 mV	TLC279MD TLC274MD	TLC279MFK TLC274MFK	TLC279MJ TLC274MJ	TLC279MN TLC274MN		

AVAILABLE OPTIONS

The D package is available taped and reeled. Add R suffix to the device type (e.g., TLC279CDR).



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



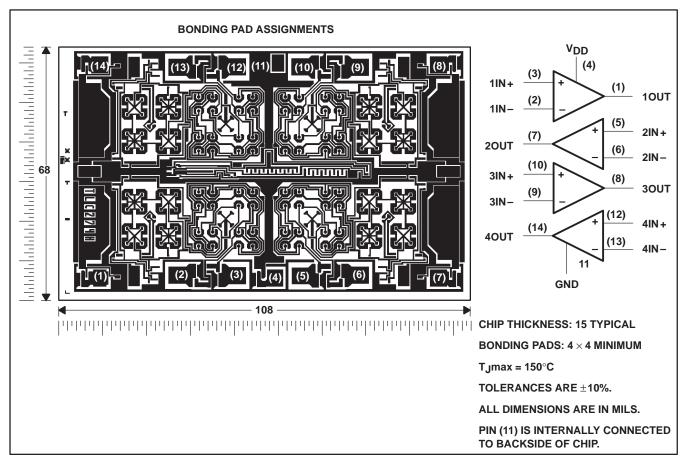
equivalent schematic (each amplifier)



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

TLC274Y chip information

These chips, when properly assembled, display characteristics similar to the TLC274C. Thermal compression or ultrasonic bonding may be used on the doped-aluminum bonding pads. Chips may be mounted with conductive epoxy or a gold-silicon preform.





SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{DD} (see Note 1) Differential input voltage, V _{ID} (see Note 2) Input voltage range, V _I (any input)	±V _{DD} to V _{DD} ±5 mA 30 mA 45 mA
Duration of short-circuit current at (or below) 25°C (see Note 3) ur	nlimited
Continuous total dissipation	g Table
Operating free-air temperature, T _A : C suffix 0°C t	o 70°C
I suffix	o 85°C
M suffix	125°C
Storage temperature range65°C to	150°C
Case temperature for 60 seconds: FK package	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: D, N, or PW package Lead temperature 1,6 mm (1/16 inch) from case for 60 seconds: J package	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential voltages, are with respect to network ground.

2. Differential voltages are at the noninverting input with respect to the inverting input.

3. The output may be shorted to either supply. Temperature and/or supply voltages must be limited to ensure that the maximum dissipation rating is not exceeded (see application section).

		DISSIPATION	KATING TABLE		
PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING	T _A = 125°C POWER RATING
D	950 mW	7.6 mW/°C	608 mW	494 mW	_
FK	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW
J	1375 mW	11.0 mW/°C	880 mW	715 mW	275 mW
N	1575 mW	12.6 mW/°C	1008 mW	819 mW	—
PW	700 mW	5.6 mW/°C	448 mW	_	—

DISSIPATION RATING TABLE

recommended operating conditions

		C SU	FFIX	I SUF	FIX	M SU	FFIX	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
Supply voltage, V _{DD}		3	16	4	16	4	16	V
	$V_{DD} = 5 V$	-0.2	3.5	-0.2	3.5	0	3.5	V
Common-mode input voltage, V _{IC}	V _{DD} = 10 V	-0.2	8.5	-0.2	8.5	0	8.5	v
Operating free-air temperature, T_A		0	70	-40	85	-55	125	°C



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

electrical characteristics at specified free-air temperature, V_{DD} = 5 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	TAT	TLC274 TLC274	C, TLC2 BC, TLC		UNIT
						MIN	TYP	MAX	
		TI 00740	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		1.1	10	
		TLC274C	$R_S = 50 \Omega$,	$R_L = 10 k\Omega$	Full range			12	
		TI 007440	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		0.9	5	mV
M	have a ffer of a self-series	TLC274AC	$R_{S} = 50 \Omega,$	$R_L = 10 k\Omega$	Full range			6.5	
VIO	Input offset voltage	TI 007 (D0	V _O = 1.4 V,	VIC = 0,	25°C		340	2000	
		TLC274BC	$R_{S} = 50 \Omega,$	$R_L = 10 k\Omega$	Full range			3000	
		TI 00700	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		320	900	μV
		TLC279C	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			1500	
ανιο	Average temperature coeffi offset voltage	cient of input			25°C to 70°C		1.8		μV/°C
	oncorvonago				25°C		0.1		
10	Input offset current (see No	te 4)	V _O = 2.5 V,	$V_{IC} = 2.5 V$	70°C	-	7	300	pА
					25°C		0.6	000	
IB	Input bias current (see Note	e 4)	V _O = 2.5 V,	V _{IC} = 2.5 V	70°C		40	600	pА
					100	-0.2	-0.3	000	
					25°C	to	to		V
VICR	Common-mode input voltag	ge range				4	4.2		
ICK	(see Note 5)					-0.2			.,
					Full range	to 3.5			V
					25°C	3.2	3.8		
∨он	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	0°C	3	3.8		V
					70°C	3	3.8		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	0°C		0	50	mV
					70°C		0	50	
					25°C	5	23		
AVD	Large-signal differential volt amplification	tage	$V_{O} = 0.25 V \text{ to } 2 V,$	$R_L = 10 \ k\Omega$	0°C	4	27		V/mV
	amplification				70°C	4	20		
					25°C	65	80		
CMRR	Common-mode rejection ra	tio	$V_{IC} = V_{ICR}min$		0°C	60	84		dB
					70°C	60	85		
					25°C	65	95		
k _{SVR}	Supply-voltage rejection rat $(\Delta V_{DD}/\Delta V_{IO})$	io	$V_{DD} = 5 V \text{ to } 10 V,$	V _O = 1.4 V	0°C	60	94		dB
					70°C	60	96		
					25°C		2.7	6.4	
IDD	Supply current (four amplifi	ers)	$V_{O} = 2.5 V$, No load	V _{IC} = 2.5 V,	0°C		3.1	7.2	mA
					70°C		2.3	5.2	

[†] Full range is 0°C to 70°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

electrical characteristics at specified free-air temperature, V_{DD} = 10 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	τ _A †	TLC274 TLC274			UNIT
						MIN	TYP	MAX	-
		TI 00740	V _O = 1.4 V,	V _{IC} = 0,	25°C		1.1	10	
		TLC274C	$R_S = 50 \Omega$,	$R_L = 10 k\Omega$	Full range			12	
		TI 007440	V _O = 1.4 V,	VIC = 0,	25°C		0.9	5	mV
	have to ffe at welter as	TLC274AC	$R_S = 50 \Omega$,	$R_L = 10 k\Omega$	Full range			6.5	
VIO	Input offset voltage	TI 0074D0	V _O = 1.4 V,	VIC = 0,	25°C		390	2000	
		TLC274BC	$R_{S} = 50 \Omega,$	$R_L = 10 k\Omega$	Full range			3000	
		TI 00700	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		370	1200	μV
		TLC279C	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			1900	
αΛΙΟ	Average temperature con input offset voltage	efficient of			25°C to 70°C		2		μV/°C
					25°C		0.1		
IIO	Input offset current (see	Note 4)	V _O =.5 V,	$V_{IC} = 5 V$	70°C		7	300	pА
					25°C		0.7		
IВ	Input bias current (see N	lote 4)	V _O = 5 V,	$V_{IC} = 5 V$	70°C		50	600	рA
						-0.2	-0.3		
Vion	Common-mode input vol	ltage range			25°C	to 9	to 9.2		V
VICR	(see Note 5)				Full range	-0.2 to 8.5			V
					25°C	8	8.5		
Vон	High-level output voltage	9	V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	0°C	7.8	8.5		V
0				-	70°C	7.8	8.4		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	0°C		0	50	mV
					70°C		0	50	
					25°C	10	36		
AVD	Large-signal differential amplification	voltage	$V_{O} = 1 V \text{ to } 6 V,$	$R_L = 10 \text{ k}\Omega$	0°C	7.5	42		V/mV
	ampinication				70°C	7.5	32		
					25°C	65	85		
CMRR	Common-mode rejection	n ratio	$V_{IC} = V_{ICR}min$		0°C	60	88		dB
					70°C	60	88		
					25°C	65	95		
ksvr	Supply-voltage rejection $(\Delta V_{DD}/\Delta V_{IO})$	ratio	$V_{DD} = 5 V \text{ to } 10 V,$	V _O = 1.4 V	0°C	60	94		dB
					70°C	60	96		
				N = 54	25°C		3.8	8	
IDD	Supply current (four amp	olifiers)	$V_{O} = 5 V$, No load	$V_{IC} = 5 V,$	0°C		4.5	8.8	mA
					70°C		3.2	6.8	

[†] Full range is 0°C to 70°C. NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

electrical characteristics at specified free-air temperature, V_{DD} = 5 V (unless otherwise noted)

	PARAMETER		TEST CONI	DITIONS	TAT		4I, TLC2 4BI, TL(UNIT
						MIN	TYP	MAX	
		TI 00741	V _O = 1.4 V,	V _{IC} = 0,	25°C		1.1	10	
		TLC274I	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			13	
		TLC274AI	V _O = 1.4 V,	VIC = 0,	25°C		0.9	5	mV
Vie	Input offect voltage	TLC274AI	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			7	
VIO	Input offset voltage	TLC274BI	V _O = 1.4 V,	VIC = 0,	25°C		340	2000	
		TLC274DI	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			3500	μV
		TLC279I	V _O = 1.4 V,	V _{IC} = 0,	25°C		320	900	μv
		1202731	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			2000	
αΛΙΟ	Average temperature coeffici offset voltage	ent of input			25°C to 85°C		1.8		μV/°C
l	Innut offent ourrent (and Note				25°C		0.1		~ ^
10	Input offset current (see Note	; 4)	V _O = 2.5 V,	$V_{IC} = 2.5 V$	85°C		24	1000	pА
lin	Input bias current (see Note	4)	V _O = 2.5 V,	VIC = 2.5 V	25°C		0.6		pА
IВ	input bias current (see Note ?	+)	$v_0 = 2.5 v_1$	VIC = 2.5 V	85°C		200	2000	рА
	Common-mode input voltage	rance			25°C	-0.2 to 4	-0.3 to 4.2		V
VICR	(see Note 5)				Full range	-0.2 to 3.5			V
					25°C	3.2	3.8		
Vон	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	-40°C	3	3.8		V
					85°C	3	3.8		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	-40°C		0	50	mV
					85°C		0	50	
					25°C	5	23		
AVD	Large-signal differential volta amplification	ge	$V_{O} = 0.25 V$ to 2 V,	$R_L = 10 \ k\Omega$	-40°C	3.5	32		V/mV
					85°C	3.5	19		
					25°C	65	80		
CMRR	Common-mode rejection ratio	D	$V_{IC} = V_{ICR}min$		-40°C	60	81		dB
				_	85°C	60	86		
					25°C	65	95		
k SVR	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{IO})$)	$V_{DD} = 5 V$ to 10 V,	V _O = 1.4 V	-40°C	60	92		dB
					85°C	60	96		
					25°C		2.7	6.4	
IDD	Supply current (four amplifier	s)	V _O = 2.5 V, No load	$V_{IC} = 2.5 V,$	-40°C		3.8	8.8	mA
					85°C		2.1	4.8	

[†] Full range is -40° C to 85° C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

electrical characteristics at specified free-air temperature, V_{DD} = 10 V (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	TAT		4I, TLC2 4BI, TL		UNIT
						MIN	TYP	MAX	
		TLC274I	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		1.1	10	
		1102/41	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			13	
		TLC274AI	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		0.9	5	mV
14.0	Innut offent veltere	TLC2/4AI	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			7	
VIO	Input offset voltage		V _O = 1.4 V,	$V_{IC} = 0,$	25°C		390	2000	
		TLC274BI	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			3500	
			V _O = 1.4 V,	$V_{IC} = 0,$	25°C		370	1200	μV
		TLC279I	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			2900	
ανιο	Average temperature coeffici offset voltage	ent of input			25°C to 85°C		2		μV/°C
	leave offered evenes of the endlede	4)			25°C		0.1		
IIO	Input offset current (see Note	: 4)	V _O = 5 V,	$V_{IC} = 5 V$	85°C		26	1000	pА
		4)			25°C		0.7		
IВ	Input bias current (see Note	4)	V _O = 5 V,	VIC = 5 V	85°C		220	2000	pА
						-0.2	-0.3		
Vien	Common-mode input voltage	range			25°C	to 9	to 9.2		V
VICR	(see Note 5)				Full range	-0.2 to 8.5			V
					25°C	8	8.5		
∨он	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \text{ k}\Omega$	-40°C	7.8	8.5		V
OII	3			L	85°C	7.8	8.5		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	IOT = 0	-40°C		0	50	mV
01				02	85°C		0	50	
					25°C	10	36		
Avd	Large-signal differential volta	ge	$V_{O} = 1 V \text{ to } 6 V,$	RL = 10 kΩ	-40°C	7	47		V/m\
. –	amplification			_	85°C	7	31		
					25°C	65	85		
CMRR	Common-mode rejection ratio)	$V_{IC} = V_{ICR}min$		-40°C	60	87		dB
					85°C	60	88		
					25°C	65	95		
^k SVR	Supply-voltage rejection ratio	1	$V_{DD} = 5 V$ to 10 V,	V _O = 1.4 V	-40°C	60	92		dB
0.11	$(\Delta V_{DD}/\Delta V_{IO})$			2	85°C	60	96		
					25°C		3.8	8	
IDD	Supply current (four amplifier	s)	$V_{O} = 5 V$,	$V_{IC} = 5 V,$	-40°C		5.5	10	mA
50		,	No load		85°C		2.9	6.4	

[†] Full range is –40°C to 85°C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

electrical characteristics at specified free-air temperature, V_{DD} = 5 V (unless otherwise noted)

			TERT CON			TLC27	4M, TLC	279M	LINUT
	PARAMETER		TEST CONI	DITIONS	τ _A †	MIN	TYP	MAX	UNIT
		TLC274M	V _O = 1.4 V,	V _{IC} = 0,	25°C		1.1	10	
V	logut offect veltere	TLC274M	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			12	mV
VIO	Input offset voltage		V _O = 1.4 V,	$V_{IC} = 0,$	25°C		320	900	
		TLC279M	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			3750	μV
αΛΙΟ	Average temperature coefficie offset voltage	ent of input			25°C to 125°C		2.1		μV/°C
li o	Input offset current (see Note	4)	V _O = 2.5 V,	V _{IC} = 2.5 V	25°C		0.1		pА
IIO	input onset current (see Note	4)	VO = 2.5 V,	vIC = 2.5 v	125°C		1.4	15	nA
lun.	Input bias current (see Note 4	I)	V _O = 2.5 V,	V _{IC} = 2.5 V	25°C		0.6		pА
IB	input bias current (see Note 2	•)	VO = 2.5 V,	VIC = 2.5 V	125°C		9	35	nA
) (Common-mode input voltage	range			25°C	0 to 4	-0.3 to 4.2		V
VICR	(see Note 5)	-			Full range	0 to 3.5			V
					25°C	3.2	3.8		
Vон	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	−55°C	3	3.8		V
					125°C	3	3.8		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	−55°C		0	50	mV
					125°C		0	50	
					25°C	5	23		
AVD	Large-signal differential voltage amplification	ge	$V_{O} = 0.25 V \text{ to } 2 V,$	$R_L = 10 \ k\Omega$	−55°C	3.5	35		V/mV
	ampinication				125°C	3.5	16		
					25°C	65	80		
CMRR	Common-mode rejection ratio)	$V_{IC} = V_{ICR}min$		−55°C	60	81		dB
					125°C	60	84		
					25°C	65	95		
k SVR	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{IO})$		$V_{DD} = 5 V$ to 10 V,	V _O = 1.4 V	−55°C	60	90		dB
					125°C	60	97		
					25°C		2.7	6.4	
IDD	Supply current (four amplifier	s)	$V_{O} = 2.5 V$, No load	V _{IC} = 2.5 V,	−55°C		4	10	mA
					125°C		1.9	4.4	

[†] Full range is -55° C to 125° C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

electrical characteristics at specified free-air temperature, V_{DD} = 10 V (unless) otherwise noted)

	DADAMETED		TEST CON		+ +	TLC27	4M, TLC	279M	111117
	PARAMETER		TEST CON	DITIONS	TAT	MIN	TYP	MAX	UNIT
		TLC274M	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		1.1	10	mV
VIO	Input offset voltage	1 LG27 4101	R _S = 50 Ω,	$R_L = 10 k\Omega$	Full range			12	IIIV
۷Ю	niput onset voltage	TLC279M	V _O = 1.4 V,	$V_{IC} = 0,$	25°C		370	1200	μV
		1027910	R _S = 50 Ω,	$R_L = 10 \ k\Omega$	Full range			4300	μv
αVIO	Average temperature coefficie offset voltage	ent of input			25°C to 125°C		2.2		μV/°C
li o	Input offset current (see Note	4)	V _O = 5 V,	V _{IC} = 5 V	25°C		0.1		pА
10	Input onset current (see Note	4)	$v_{O} = 5 v,$	vIC = 2 v	125°C		1.8	15	nA
lun.	Input bias current (see Note 4	`	V _O = 5 V,	VIC = 5 V	25°C		0.7		pА
IВ	input bias current (see Note 4)	VO = 5 V,	AIC = 2 A	125°C		10	35	nA
N/	Common-mode input voltage	range			25°C	0 to 9	-0.3 to 9.2		V
VICR	(see Note 5)				Full range	0 to 8.5			V
					25°C	8	8.5		
Vон	High-level output voltage		V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	−55°C	7.8	8.5		V
					125°C	7.8	8.4		
					25°C		0	50	
VOL	Low-level output voltage		$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$	−55°C		0	50	mV
					125°C		0	50	
					25°C	10	36		
AVD	Large-signal differential voltage amplification	le	$V_{O} = 1 V \text{ to } 6 V,$	$R_L = 10 \ k\Omega$	−55°C	7	50		V/mV
	ampinioation				125°C	7	27		
					25°C	65	85		
CMRR	Common-mode rejection ratio		$V_{IC} = V_{ICR}min$		−55°C	60	87		dB
					125°C	60	86		
	Owner have all the second section of the				25°C	65	95		
ksvr	Supply-voltage rejection ratio $(\Delta V_{DD}/\Delta V_{IO})$		$V_{DD} = 5 V \text{ to } 10 V,$	V _O = 1.4 V	−55°C	60	90		dB
					125°C	60	97		
					25°C		3.8	8	
IDD	Supply current (four amplifiers	5)	$V_{O} = 5 V$, No load	V _{IC} = 5 V,	−55°C		6.0	12	mA
					125°C		2.5	5.6	

[†] Full range is -55° C to 125° C.

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

operating characteristics at specified free-air temperature, V_{DD} = 5 V

	PARAMETER	TEST CC	ONDITIONS	т _А		C, TLC2 .C274AC IBC, TLC	,	UNIT
					MIN	TYP	MAX	
				25°C		3.6		
			VIPP = 1 V	0°C		4		
SR	Slew rate at unity gain	$R_{L} = 10 \Omega,$		70°C		3		V/µs
SK	Siew rate at unity gain	C _L = 20 _P F, See Figure 1		25°C		2.9		v/µs
		5	V _{IPP} = 2.5 V	0°C		3.1		
				70°C		2.5		
V _n	Equivalent input noise voltage	f = 1 kHz, See Figure 2	$R_{S} = 20 \Omega$,	25°C		25		nV/√Hz
				25°C		320		
Вом	Maximum output-swing bandwidth	V _O = V _{OH} , R _L = 10 kΩ,	C _L = 20 _P F, See Figure 1	0°C		340		kHz
		11 - 10 132,	Occ riguie i	70°C	260			
				25°C		1.7		
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	0°C		2		MHz
		occ rigure o		70°C		1.3		
		10	()	25°C		46°		
φm	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	f = B ₁ ,	0°C		47°		
				70°C		44°		

operating characteristics at specified free-air temperature, V_{DD} = 10 V

	PARAMETER	TEST CO	NDITIONS	TA	TLC274C, TLC2 TLC274BC	UNIT	
					MIN T	YP MAX	
				25°C		5.3	
			V _{IPP} = 1 V	0°C		5.9	
SR	Slew rate at unity gain	$R_L = 10 \Omega$,		70°C		4.3	V/μs
	Siew rate at unity gain	C _L = 20 _P F, See Figure 1		25°C		4.6	v/µS
		3	VIPP = 5.5 V	0°C		5.1	
				70°C		3.8	
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C		25	nV/√Hz
				25°C	:	200	
ВОМ	Maximum output-swing bandwidth	V _O = V _{OH} , R _L = 10 kΩ,	C _L = 20 _P F, See Figure 1	0°C	:	220	kHz
		TKL = 10 K32,	Occ righter	70°C		140	
				25°C		2.2	
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	0°C		2.5	MHz
		occ rigare e		70°C		1.8	
		10	(25°C		49°	
фт	Phase margin	V _I = 10 mV, C _L = 20 _P F,	f = B ₁ , See Figure 3	0°C		50°	
				70°C		46°	



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

	PARAMETER	TEST C	TEST CONDITIONS		TLC274I, TLC274A TLC274BI, TLC279			UNIT
				TA	MIN TYP 3.6 4.5 2.8 2.9 3.5 2.3 2.9 3.5 2.3 25 380 250 1.7 2.6 1.2 1.2	MAX		
				25°C		3.6		
			V _{IPP} = 1 V	-40°C		4.5		
SR	Slew rate at unity gain	R _L = 10 kΩ, C _L = 20 pF,		85°C		2.8		V/µs
SK	Siew rate at unity gain	See Figure 1		25°C		2.9		v/µS
			VIPP = 2.5 V	-40°C		3.5		
						2.3		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C		25		nV/√Hz
			C _L = 20 _P F, See Figure 1	25°C		320		
ВОМ		$V_O = V_{OH},$ $R_I = 10 k\Omega,$		-40°C		380		kHz
			occ rigare r	85°C		250		
				25°C		1.7		
В ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	-40°C		2.6		MHz
				85°C		1.2		
		10	t D	25°C		46°		
φm	Phase margin	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$		-40°C		49°		
		$O_{L} = 20 \text{ pr}, \qquad \text{Occ} + \text{igure } 0$		85°C		43°		

operating characteristics at specified free-air temperature, V_{DD} = 5 V

operating characteristics at specified free-air temperature, V_{DD} = 10 V

PARAMETER		PARAMETER TEST CONDITIONS		ТА	TLC274I, TLC2 TLC274BI, TL		UNIT						
				~	MIN TYP	MAX							
				25°C	5.3								
			V _{IPP} = 1 V	-40°C	6.7								
SR	Slow rote at unity gain	$R_L = 10 \Omega$,		85°C	4		1//110						
SK	Slew rate at unity gain	C _L = 20 pF, See Figure 1		25°C	4.6		V/μs						
			VIPP = 5.5 V	-40°C	5.8								
				85°C	3.5								
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C	25		nV/√Hz						
		$\label{eq:VO} \begin{array}{c} V_O = V_{OH}, \qquad C_L = 20 \ \text{pF}, \\ R_L = 10 \ \text{k}\Omega, \qquad \text{See Figure 1} \end{array} \begin{array}{c} 25^\circ\text{C} \\ \hline -40^\circ\text{C} \\ 85^\circ\text{C} \end{array}$				25°C	200						
ВОМ	Maximum output-swing bandwidth		-40°C	260		kHz							
			85°C	130									
				25°C	2.2								
B ₁	Unity-gain bandwidth	VI = 10 mV, See Figure 3	C _L = 20 _P F,	-40°C	3.1		MHz						
		See Figure 3		85°C	1.7								
		10	()	25°C	49°								
φ _m	Phase margin	$V_{I} = 10 \text{ mV},$				V _I = 10 mV, C _L = 20 pF,			f = B ₁ , See Figure 3	-40°C	52°		
			Pr, Ocerngule 5		46°								



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

operating characteristics at specified free-air temperature, $V_{DD} = 5 V$

	DADAMETED	TEST OO	NDITIONS	-	TLC274	4M, TLC	279M	LINUT				
	PARAMETER	TEST CO	NDITIONS	TA	MIN	TYP	MAX	UNIT				
				25°C		3.6						
			VIPP = 1 V	−55°C		4.7						
SR	Slow rote of unity goin	$R_L = 10 k\Omega$,		125°C		2.3	.3)//uo				
SK	Slew rate at unity gain	$C_L = 20 \text{ pF},$ See Figure 1 $V_{IPP} = 2.5 \text{ V}$			25°C		2.9		V/µs			
			−55°C		3.7							
			125°C		2							
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C		25		nV/√Hz				
		iximum output-swing bandwidth $V_O = V_{OH}$, $C_L = 20 \text{ pF}$, $R_L = 10 \text{ k}\Omega$, See Figure 1	vidth $V_O = V_{OH}$, $C_L = 20 \text{ pF}$, $R_L = 10 \text{ k}\Omega$, See Figure 1	Maximum output-swing bandwidth $V_O = V_{OH}$, $C_L = 20 \text{ pF}$, $R_L = 10 \text{ k}\Omega$, See Figure 1		25°C		320				
BOM	Maximum output-swing bandwidth				$V_O = V_{OH}$	VO = VOH	C _L = 20 pF, See Figure 1	−55°C		400		kHz
					125°C		230					
			o	25°C		1.7						
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	−55°C		2.9		MHz				
					igure 5	125°C		1.1				
		10	(25°C		46°						
φm	Phase margin	V _I = 10 mV, C _I = 20 pF,	f = B ₁ , See Figure 3	−55°C		49°						
		$O_L = 20 \text{ pr}, \qquad \text{See Figure 3}$		$O_L = 20 \text{ pr}, \qquad \text{See Figure 5}$	eeeguio o	125°C		41°				

operating characteristics at specified free-air temperature, $V_{\mbox{DD}}$ = 10 V

	DADAMETED	TEST OF		τ.	TLC274	M, TLC	279M	LINUT		
	PARAMETER	TESTCO	ONDITIONS	TA	MIN	TYP	MAX	UNIT		
				25°C		5.3				
			VIPP = 1 V	−55°C		7.1				
SR	Slow rote at unity goin	$R_L = 10 \Omega$,		125°C		3.1		1///10		
SK	Slew rate at unity gain	C _L = 20 _P F, See Figure 1		25°C		4.6		V/μs		
		J	V _{IPP} = 5.5 V	−55°C		6.1				
		I I F				125°C		2.7		
Vn	Equivalent input noise voltage	f = 1 kHz, See Figure 2	R _S = 20 Ω,	25°C		25		nV/√Hz		
		$V_O = V_{OH}$, $C_L = 20 \text{ pF}$, $R_L = 10 \text{ k}\Omega$, See Figure 1		$V_{O} = V_{OH}$		25°C		200		
ВОМ	Maximum output-swing bandwidth					−55°C		280		kHz
				, Occrigater	125°C		110			
				a	25°C		2.2			
B ₁	Unity-gain bandwidth	V _I = 10 mV, See Figure 3	C _L = 20 _P F,	−55°C		3.4		MHz		
			ose rigure s	125°C		1.6				
			(25°C		49°				
φm	Phase margin		$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF},$	$V_{I} = 10 \text{ mV},$ $C_{L} = 20 \text{ pF}$	f = B ₁ , See Figure 3	−55°C		52°		
			eeegalo o	125°C		44°				



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

electrical characteristics, V_{DD} = 5 V, T_A = 25°C (unless otherwise noted)

	DADAMETED	TEST CON	DITIONS	TLC274Y			
	PARAMETER	ETER TEST CONDITIONS		MIN	TYP	MAX	UNIT
VIO	Input offset voltage	$V_{O} = 1.4 V,$ R _S = 50 Ω ,	$V_{IC} = 0,$ R _L = 10 k Ω		1.1	10	mV
Iю	Input offset current (see Note 4)	V _O = 2.5 V,	V _{IC} = 2.5 V		0.1		pА
I _{IB}	Input bias current (see Note 4)	V _O = 2.5 V,	V _{IC} = 2.5 V		0.6		pА
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 4	-0.3 to 4.2		V
∨он	High-level output voltage	V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	3.2	3.8		V
VOL	Low-level output voltage	V _{ID} = -100 mV,	IOT = 0		0	50	mV
A _{VD}	Large-signal differential voltage amplification	$V_{O} = 0.25 \text{ V to 2 V},$	$R_L = 10 \text{ k}\Omega$	5	23		V/mV
CMRR	Common-mode rejection ratio	$V_{IC} = V_{ICR}min$		65	80		dB
k SVR	Supply-voltage rejection ratio ($\Delta V_{DD}/\Delta V_{IO}$)	V _{DD} = 5 V to 10 V,	V _O = 1.4 V	65	95		dB
IDD	Supply current (four amplifiers)	V _O = 2.5 V, No load	V _{IC} = 2.5 V,		2.7	6.4	mA

electrical characteristics, V_{DD} = 10 V, T_A = 25°C (unless otherwise noted)

	PARAMETER			т	LC274Y		UNIT
			TEST CONDITIONS		TYP	MAX	UNIT
VIO	Input offset voltage	$V_{O} = 1.4 V,$ R _S = 50 Ω ,	$V_{IC} = 0,$ $R_L = 10 \text{ k}\Omega$		1.1	10	mV
Iю	Input offset current (see Note 4)	V _O = 5 V,	V _{IC} = 5 V		0.1		pА
I _{IB}	Input bias current (see Note 4)	V _O = 5 V,	$V_{IC} = 5 V$		0.7		pА
VICR	Common-mode input voltage range (see Note 5)			-0.2 to 9	-0.3 to 9.2		V
∨он	High-level output voltage	V _{ID} = 100 mV,	$R_L = 10 \ k\Omega$	8	8.5		V
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV},$	$I_{OL} = 0$		0	50	mV
AVD	Large-signal differential voltage amplification	$V_{O} = 1 V \text{ to } 6 V,$	$R_L = 10 \ k\Omega$	10	36		V/mV
CMRR	Common-mode rejection ratio	$V_{IC} = V_{ICR}min$		65	85		dB
k SVR	Supply-voltage rejection ratio $(\Delta V_{DD} / \Delta V_{IO})$	$V_{DD} = 5 V \text{ to } 10 V,$	V _O = 1.4 V	65	95		dB
I _{DD}	Supply current (four amplifiers)	V _O = 5 V, No load	V _{IC} = 5 V,		3.8	8	mA

NOTES: 4. The typical values of input bias current and input offset current below 5 pA were determined mathematically.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

operating characteristics, V_{DD} = 5 V, T_A = 25°C

PARAMETER		_	TEST CONDITIONS			TLC274Y		
	FARAMETER	TEST CONDITIONS		13	MIN	TYP	MAX	UNIT
SR	Slew rate at unity gain	$R_L = 10 \text{ k}\Omega$,	C _L = 20 _P F,	$V_{IPP} = 1 V$		3.6		V/µs
SK	Siew fate at unity gain	See Figure 1		VIPP = 2.5 V		2.9		ν/μ5
Vn	Equivalent input noise voltage	f = 1 kHz,	R _S = 20 Ω,	See Figure 2		25		nV/√Hz
вом	Maximum output-swing bandwidth	V _O = V _{OH} , See Figure 1	C _L = 20 _P F,	R _L = 10 kΩ,		320		kHz
B ₁	Unity-gain bandwidth	V _I = 10 mV,	C _L = 20 _P F,	See Figure 3		1.7		MHz
φ _m	Phase margin	V _I = 10 mV, See Figure 3	$f = B_1,$	C _L = 20 pF,		46°		

operating characteristics, V_{DD} = 10 V, T_A = 25°C

PARAMETER			TEST CONDITIONS			TLC274Y		
	FARAMETER	PARAMETER TEST CONDITIONS		15	MIN TYP		MAX	UNIT
SR	Slew rate at unity gain	R _L = 10 kΩ,	C _L = 20 _P F,	$V_{IPP} = 1 V$		5.3		V/µs
J.	Siew rate at unity gain	See Figure 1		VIPP = 5.5 V		4.6		·
Vn	Equivalent input noise voltage	f = 1 kHz,	R _S = 20 Ω,	See Figure 2		25		nV/√Hz
B _{OM}	Maximum output-swing bandwidth	V _O = V _{OH} , See Figure 1	C _L = 20 _P F,	R _L = 10 kΩ,		200		kHz
B ₁	Unity-gain bandwidth	V _I = 10 mV,	C _L = 20 _P F,	See Figure 3		2.2		MHz
φ _m	Phase margin	V _I = 10 mV, See Figure 3	$f = B_1,$	C _L = 20 _P F,		49°		

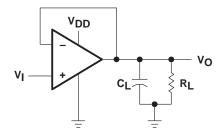


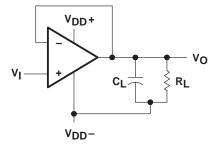
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

PARAMETER MEASUREMENT INFORMATION

single-supply versus split-supply test circuits

Because the TLC274 and TLC279 are optimized for single-supply operation, circuit configurations used for the various tests often present some inconvenience since the input signal, in many cases, must be offset from ground. This inconvenience can be avoided by testing the device with split supplies and the output load tied to the negative rail. A comparison of single-supply versus split-supply test circuits is shown below. The use of either circuit gives the same result.

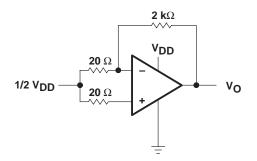


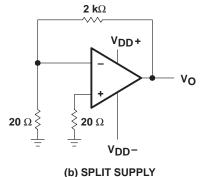




(b) SPLIT SUPPLY

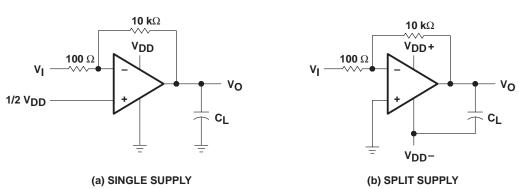






(a) SINGLE SUPPLY









SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

PARAMETER MEASUREMENT INFORMATION

input bias current

Because of the high input impedance of the TLC274 and TLC279 operational amplifiers, attempts to measure the input bias current can result in erroneous readings. The bias current at normal room ambient temperature is typically less than 1 pA, a value that is easily exceeded by leakages on the test socket. Two suggestions are offered to avoid erroneous measurements:

- 1. Isolate the device from other potential leakage sources. Use a grounded shield around and between the device inputs (see Figure 4). Leakages that would otherwise flow to the inputs are shunted away.
- 2. Compensate for the leakage of the test socket by actually performing an input bias current test (using a picoammeter) with no device in the test socket. The actual input bias current can then be calculated by subtracting the open-socket leakage readings from the readings obtained with a device in the test socket.

One word of caution: many automatic testers as well as some bench-top operational amplifier testers use the servo-loop technique with a resistor in series with the device input to measure the input bias current (the voltage drop across the series resistor is measured and the bias current is calculated). This method requires that a device be inserted into the test socket to obtain a correct reading; therefore, an open-socket reading is not feasible using this method.

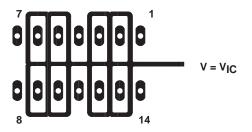


Figure 4. Isolation Metal Around Device Inputs (J and N packages)

low-level output voltage

To obtain low-supply-voltage operation, some compromise was necessary in the input stage. This compromise results in the device low-level output being dependent on both the common-mode input voltage level as well as the differential input voltage level. When attempting to correlate low-level output readings with those quoted in the electrical specifications, these two conditions should be observed. If conditions other than these are to be used, please refer to Figures 14 through 19 in the Typical Characteristics of this data sheet.

input offset voltage temperature coefficient

Erroneous readings often result from attempts to measure temperature coefficient of input offset voltage. This parameter is actually a calculation using input offset voltage measurements obtained at two different temperatures. When one (or both) of the temperatures is below freezing, moisture can collect on both the device and the test socket. This moisture results in leakage and contact resistance, which can cause erroneous input offset voltage readings. The isolation techniques previously mentioned have no effect on the leakage since the moisture also covers the isolation metal itself, thereby rendering it useless. It is suggested that these measurements be performed at temperatures above freezing to minimize error.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

PARAMETER MEASUREMENT INFORMATION

full-power response

Full-power response, the frequency above which the operational amplifier slew rate limits the output voltage swing, is often specified two ways: full-linear response and full-peak response. The full-linear response is generally measured by monitoring the distortion level of the output while increasing the frequency of a sinusoidal input signal until the maximum frequency is found above which the output contains significant distortion. The full-peak response is defined as the maximum output frequency, without regard to distortion, above which full peak-to-peak output swing cannot be maintained.

Because there is no industry-wide accepted value for significant distortion, the full-peak response is specified in this data sheet and is measured using the circuit of Figure 1. The initial setup involves the use of a sinusoidal input to determine the maximum peak-to-peak output of the device (the amplitude of the sinusoidal wave is increased until clipping occurs). The sinusoidal wave is then replaced with a square wave of the same amplitude. The frequency is then increased until the maximum peak-to-peak output can no longer be maintained (Figure 5). A square wave is used to allow a more accurate determination of the point at which the maximum peak-to-peak output is reached.

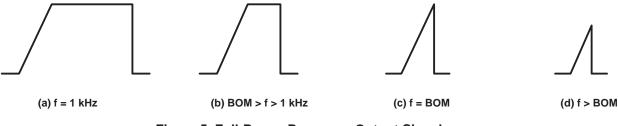


Figure 5. Full-Power-Response Output Signal

test time

Inadequate test time is a frequent problem, especially when testing CMOS devices in a high-volume, short-test-time environment. Internal capacitances are inherently higher in CMOS than in bipolar and BiFET devices and require longer test times than their bipolar and BiFET counterparts. The problem becomes more pronounced with reduced supply levels and lower temperatures.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

TYPICAL CHARACTERISTICS

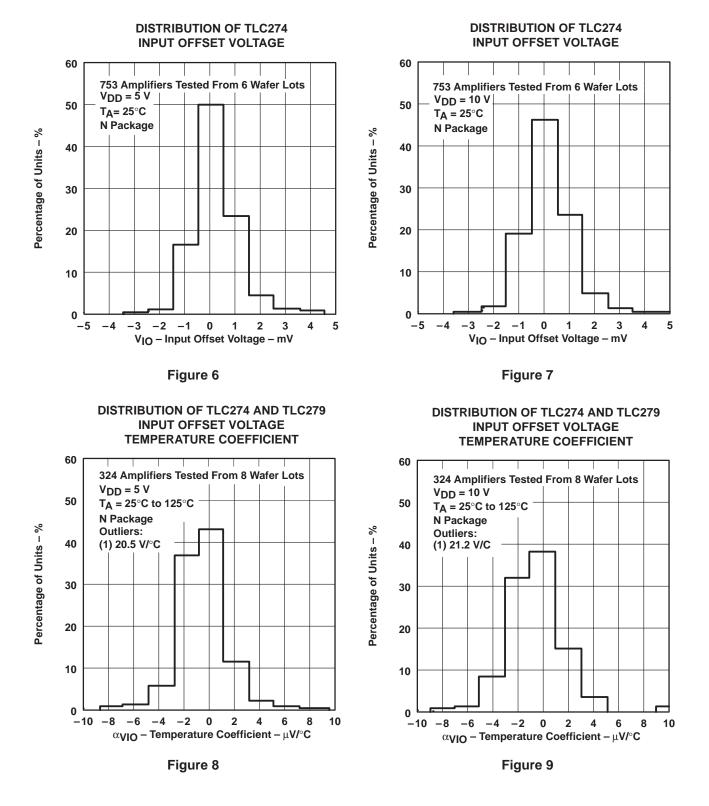
			FIGURE
VIO	Input offset voltage	Distribution	6, 7
ανιο	Temperature coefficient of input offset voltage	Distribution	8, 9
VOH	High-level output voltage	vs High-level output current vs Supply voltage vs Free-air temperature	10, 11 12 13
VOL	Low-level output voltage	vs Common-mode input voltage vs Differential input voltage vs Free-air temperature vs Low-level output current	14, 15 16 17 18, 19
AVD	Large-signal differential voltage amplification	vs Supply voltage vs Free-air temperature vs Frequency	20 21 32, 33
I _{IB}	Input bias current	vs Free-air temperature	22
IIO	Input offset current	vs Free-air temperature	22
VIC	Common-mode input voltage	vs Supply voltage	23
IDD	Supply current	vs Supply voltage vs Free-air temperature	24 25
SR	Slew rate	vs Supply voltage vs Free-air temperature	26 27
	Normalized slew rate	vs Free-air temperature	28
V _{O(PP)}	Maximum peak-to-peak output voltage	vs Frequency	29
B ₁	Unity-gain bandwidth	vs Free-air temperature vs Supply voltage	30 31
фт	Phase margin	vs Supply voltage vs Free-air temperature vs Load capacitance	34 35 36
V _n	Equivalent input noise voltage	vs Frequency	37
	Phase shift	vs Frequency	32, 33

Table of Graphs



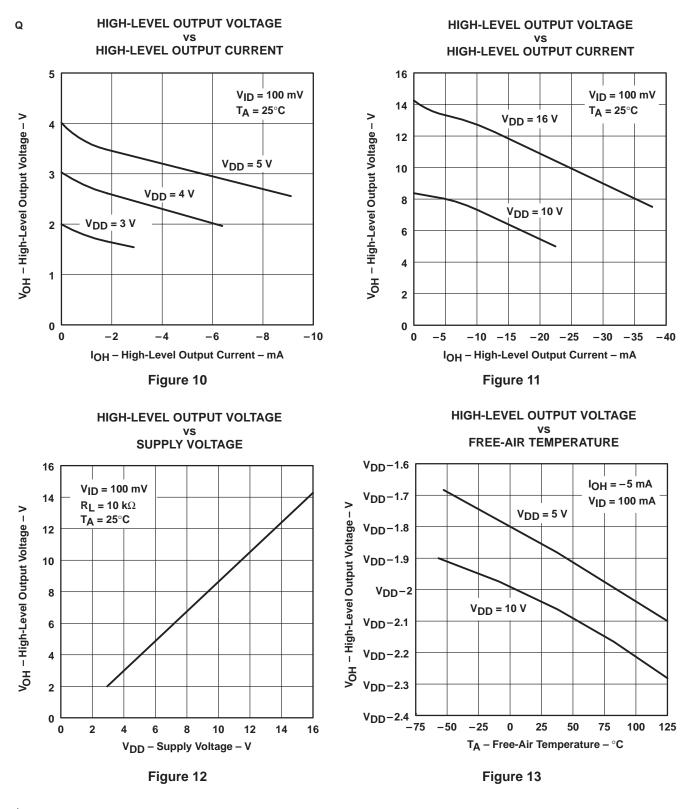
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

TYPICAL CHARACTERISTICS





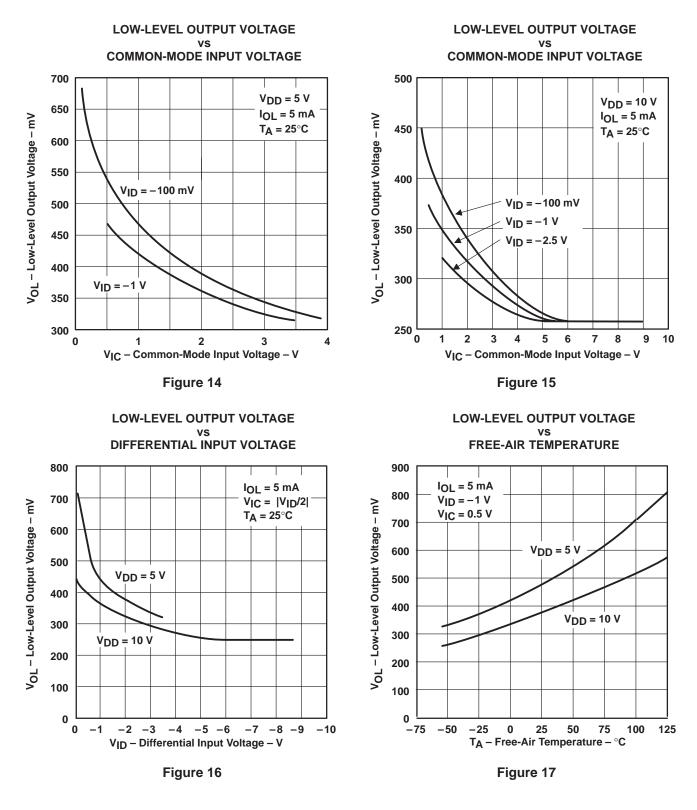
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



TYPICAL CHARACTERISTICS[†]



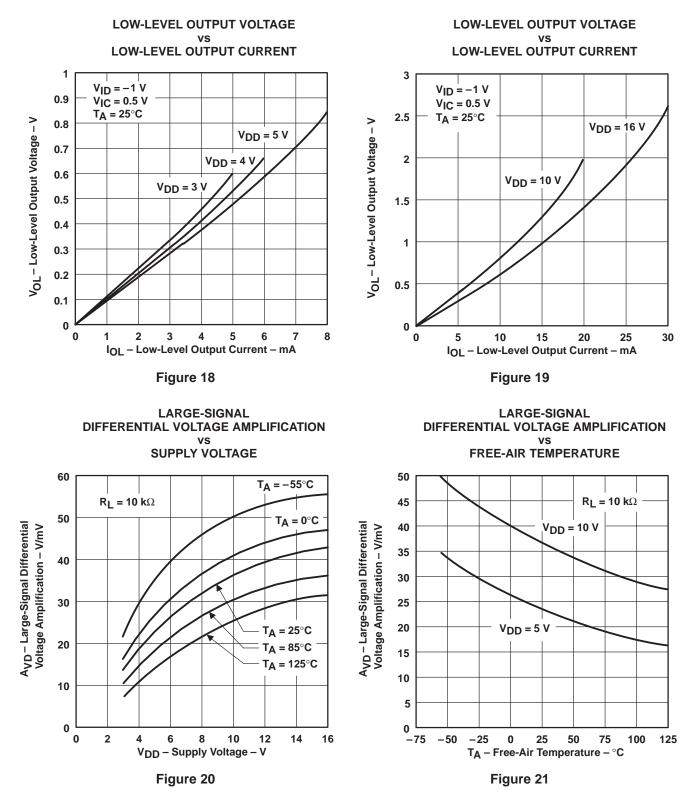
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



TYPICAL CHARACTERISTICS[†]



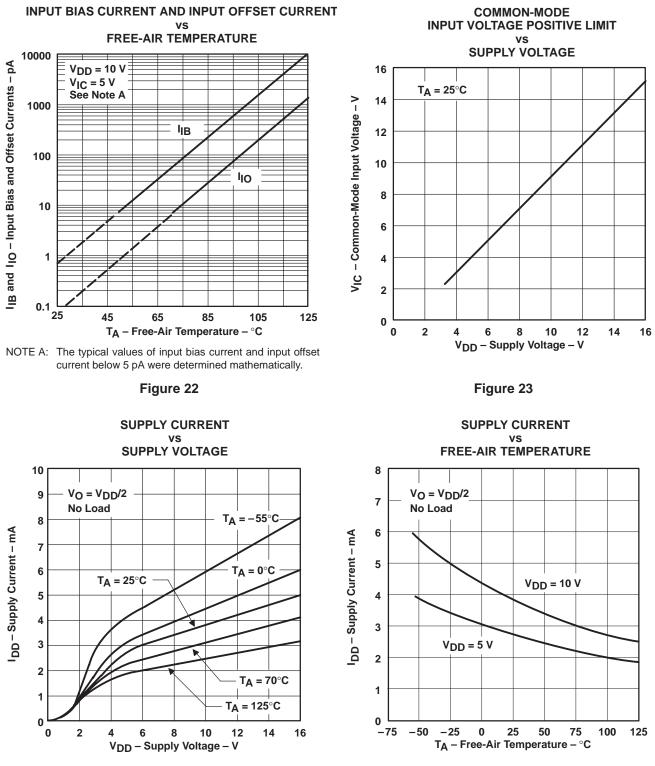
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



TYPICAL CHARACTERISTICS[†]



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



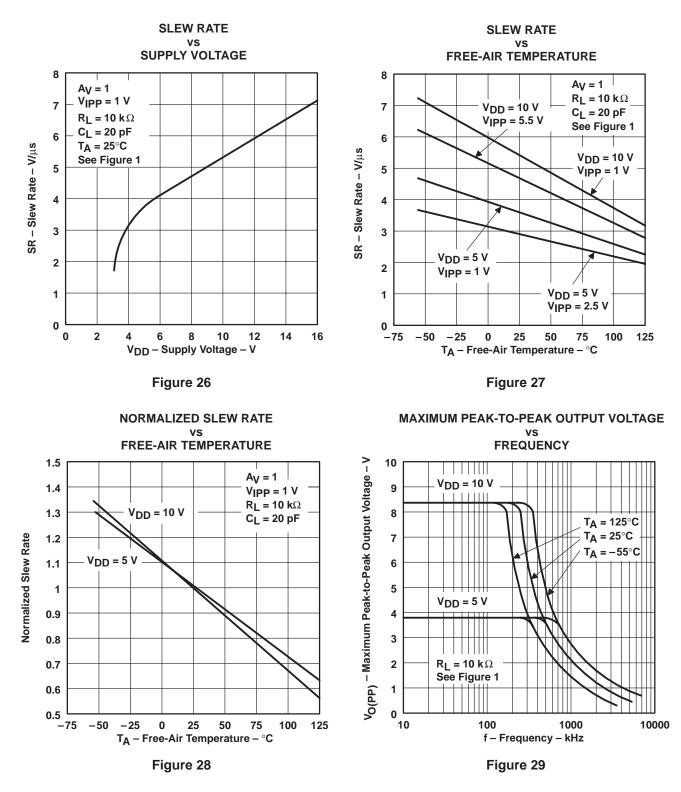
TYPICAL CHARACTERISTICS[†]

Figure 24

Figure 25



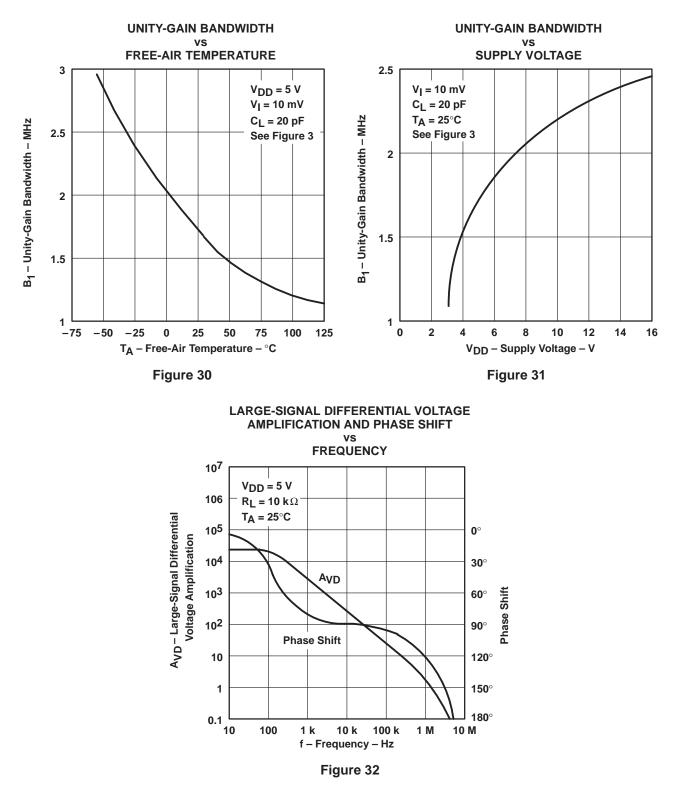
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



TYPICAL CHARACTERISTICS[†]



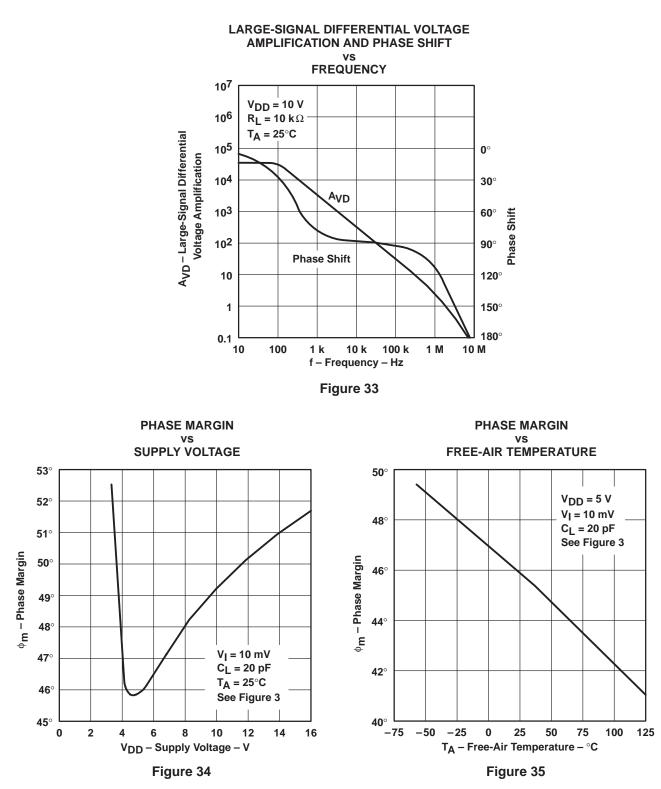
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



TYPICAL CHARACTERISTICS[†]



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

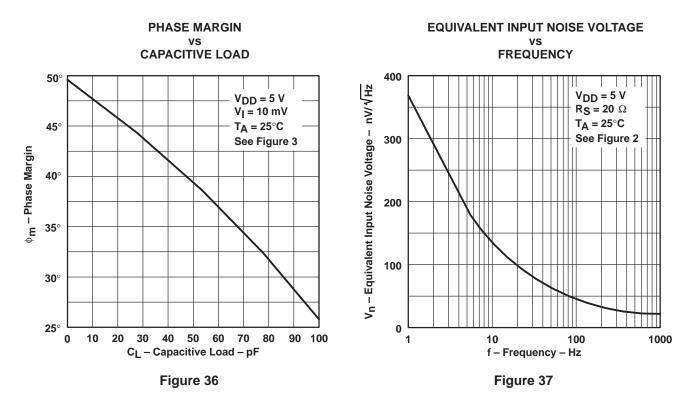


TYPICAL CHARACTERISTICS[†]



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

TYPICAL CHARACTERISTICS





SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

APPLICATION INFORMATION

single-supply operation

While the TLC274 and TLC279 perform well using dual power supplies (also called balanced or split supplies), the design is optimized for single-supply operation. This design includes an input common-mode voltage range that encompasses ground as well as an output voltage range that pulls down to ground. The supply voltage range extends down to 3 V (C-suffix types), thus allowing operation with supply levels commonly available for TTL and HCMOS; however, for maximum dynamic range, 16-V single-supply operation is recommended.

Many single-supply applications require that a voltage be applied to one input to establish a reference level that is above ground. A resistive voltage divider is usually sufficient to establish this reference level (see Figure 38). The low input bias current of the TLC274 and TLC279 permits the use of very large resistive values to implement the voltage divider, thus minimizing power consumption.

The TLC274 and TLC279 work well in conjunction with digital logic; however, when powering both linear devices and digital logic from the same power supply, the following precautions are recommended:

- 1. Power the linear devices from separate bypassed supply lines (see Figure 39); otherwise the linear device supply rails can fluctuate due to voltage drops caused by high switching currents in the digital logic.
- 2. Use proper bypass techniques to reduce the probability of noise-induced errors. Single capacitive decoupling is often adequate; however, high-frequency applications may require R_C decoupling.

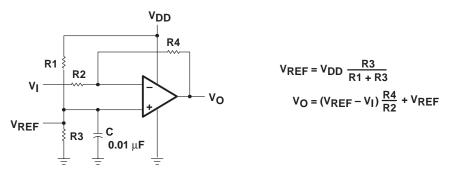
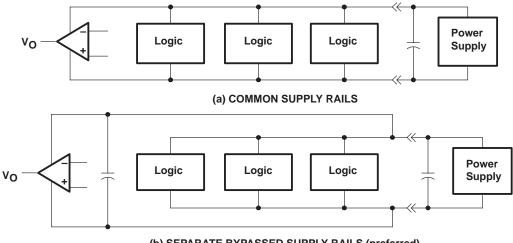


Figure 38. Inverting Amplifier With Voltage Reference



(b) SEPARATE BYPASSED SUPPLY RAILS (preferred)

Figure 39. Common Versus Separate Supply Rails



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

APPLICATION INFORMATION

input characteristics

The TLC274 and TLC279 are specified with a minimum and a maximum input voltage that, if exceeded at either input, could cause the device to malfunction. Exceeding this specified range is a common problem, especially in single-supply operation. Note that the lower range limit includes the negative rail, while the upper range limit is specified at $V_{DD} - 1$ V at $T_A = 25^{\circ}$ C and at $V_{DD} - 1.5$ V at all other temperatures.

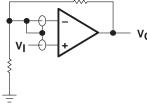
The use of the polysilicon-gate process and the careful input circuit design gives the TLC274 and TLC279 very good input offset voltage drift characteristics relative to conventional metal-gate processes. Offset voltage drift in CMOS devices is highly influenced by threshold voltage shifts caused by polarization of the phosphorus dopant implanted in the oxide. Placing the phosphorus dopant in a conductor (such as a polysilicon gate) alleviates the polarization problem, thus reducing threshold voltage shifts by more than an order of magnitude. The offset voltage drift with time has been calculated to be typically 0.1 μ V/month, including the first month of operation.

Because of the extremely high input impedance and resulting low bias current requirements, the TLC274 and TLC279 are well suited for low-level signal processing; however, leakage currents on printed-circuit boards and sockets can easily exceed bias current requirements and cause a degradation in device performance. It is good practice to include guard rings around inputs (similar to those of Figure 4 in the Parameter Measurement Information section). These guards should be driven from a low-impedance source at the same voltage level as the common-mode input (see Figure 40).

Unused amplifiers should be connected as grounded unity-gain followers to avoid possible oscillation.

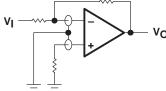
noise performance

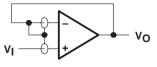
The noise specifications in operational amplifier circuits are greatly dependent on the current in the first-stage differential amplifier. The low input bias current requirements of the TLC274 and TLC279 result in a very low noise current, which is insignificant in most applications. This feature makes the devices especially favorable over bipolar devices when using values of circuit impedance greater than 50 k Ω , since bipolar devices exhibit greater noise currents.





(a) NONINVERTING AMPLIFIER





(b) INVERTING AMPLIFIER

(c) UNITY-GAIN AMPLIFIER

Figure 40. Guard-Ring Schemes

output characteristics

The output stage of the TLC274 and TLC279 is designed to sink and source relatively high amounts of current (see typical characteristics). If the output is subjected to a short-circuit condition, this high current capability can cause device damage under certain conditions. Output current capability increases with supply voltage.

All operating characteristics of the TLC274 and TLC279 were measured using a 20-pF load. The devices drive higher capacitive loads; however, as output load capacitance increases, the resulting response pole occurs at lower frequencies, thereby causing ringing, peaking, or even oscillation (see Figure 41). In many cases, adding a small amount of resistance in series with the load capacitance alleviates the problem.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

APPLICATION INFORMATION

output characteristics (continued)

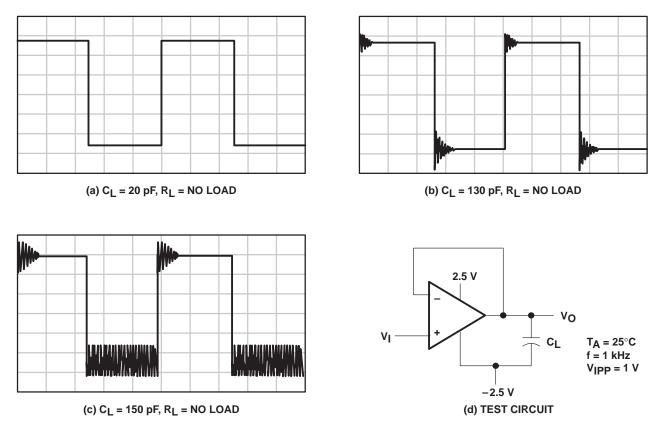


Figure 41. Effect of Capacitive Loads and Test Circuit

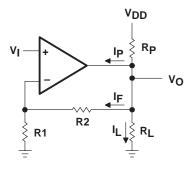
Although the TLC274 and TLC279 possess excellent high-level output voltage and current capability, methods for boosting this capability are available, if needed. The simplest method involves the use of a pullup resistor (R_p) connected from the output to the positive supply rail (see Figure 42). There are two disadvantages to the use of this circuit. First, the NMOS pulldown transistor N4 (see equivalent schematic) must sink a comparatively large amount of current. In this circuit, N4 behaves like a linear resistor with an on-resistance between approximately 60Ω and 180Ω , depending on how hard the op amp input is driven. With very low values of R_P, a voltage offset from 0 V at the output occurs. Second, pullup resistor R_P acts as a drain load to N4 and the gain of the operational amplifier is reduced at output voltage levels where N5 is not supplying the output current.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

APPLICATION INFORMATION

output characteristics (continued)





Ip = Pullup current required by the operational amplifier (typically 500 μ A)

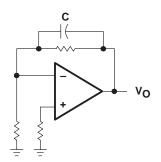


Figure 43. Compensation for Input Capacitance

Figure 42. Resistive Pullup to Increase VOH

feedback

Operational amplifier circuits nearly always employ feedback, and since feedback is the first prerequisite for oscillation, some caution is appropriate. Most oscillation problems result from driving capacitive loads (discussed previously) and ignoring stray input capacitance. A small-value capacitor connected in parallel with the feedback resistor is an effective remedy (see Figure 43). The value of this capacitor is optimized empirically.

electrostatic discharge protection

The TLC274 and TLC279 incorporate an internal electrostatic discharge (ESD) protection circuit that prevents functional failures at voltages up to 2000 V as tested under MIL-STD-883C, Method 3015.2. Care should be exercised, however, when handling these devices as exposure to ESD may result in the degradation of the device parametric performance. The protection circuit also causes the input bias currents to be temperature-dependent and have the characteristics of a reverse-biased diode.

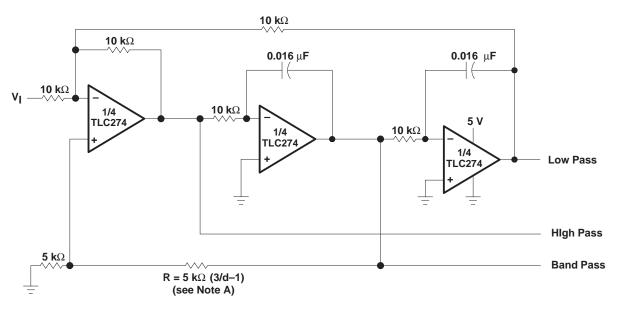
latch-up

Because CMOS devices are susceptible to latch-up due to their inherent parasitic thyristors, the TLC274 and TLC279 inputs and outputs were designed to withstand -100-mA surge currents without sustaining latch-up; however, techniques should be used to reduce the chance of latch-up whenever possible. Internal protection diodes should not, by design, be forward biased. Applied input and output voltage should not exceed the supply voltage by more than 300 mV. Care should be exercised when using capacitive coupling on pulse generators. Supply transients should be shunted by the use of decoupling capacitors (0.1 μ F typical) located across the supply rails as close to the device as possible.

The current path established if latch-up occurs is usually between the positive supply rail and ground and can be triggered by surges on the supply lines and/or voltages on either the output or inputs that exceed the supply voltage. Once latch-up occurs, the current flow is limited only by the impedance of the power supply and the forward resistance of the parasitic thyristor and usually results in the destruction of the device. The chance of latch-up occurring increases with increasing temperature and supply voltages.



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



APPLICATION INFORMATION



Figure 44. State-Variable Filter

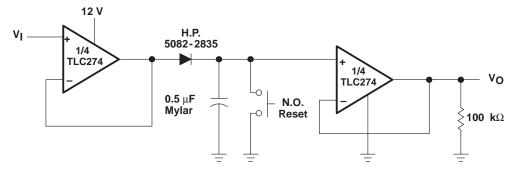
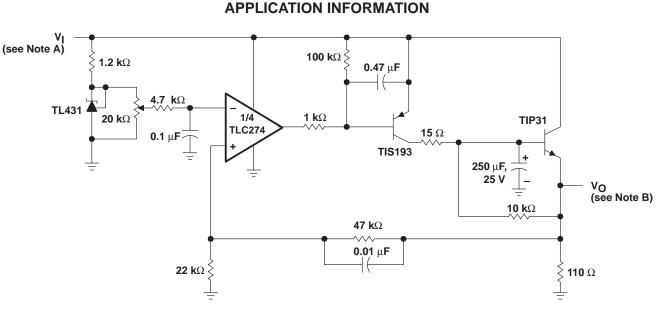


Figure 45. Positive-Peak Detector



SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998



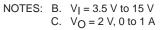
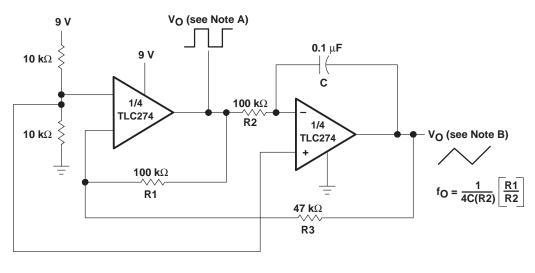


Figure 46. Logic-Array Power Supply



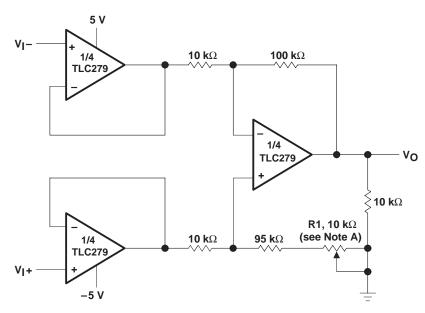
NOTES: A. $V_{O(PP)} = 8 V$ B. $V_{O(PP)} = 4 V$





SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

APPLICATION INFORMATION



NOTE C: CMRR adjustment must be noninductive.



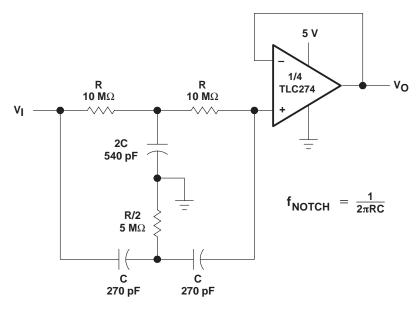


Figure 49. Single-Supply Twin-T Notch Filter

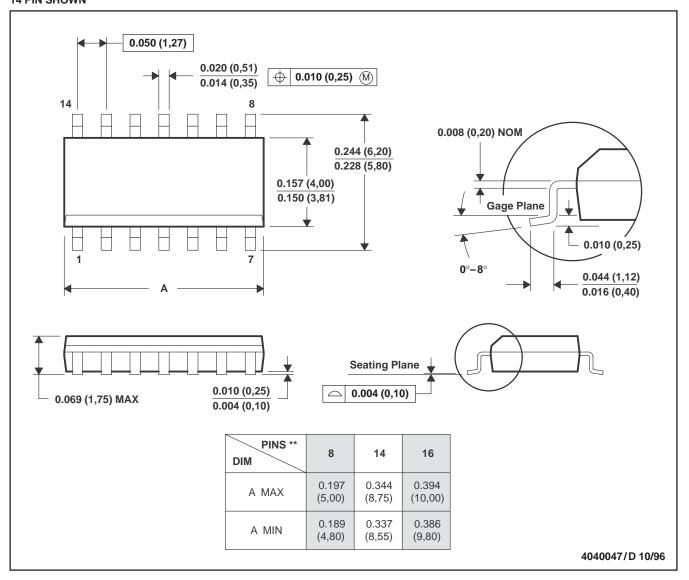


SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

MECHANICAL INFORMATION

PLASTIC SMALL-OUTLINE PACKAGE





NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).

D. Falls within JEDEC MS-012



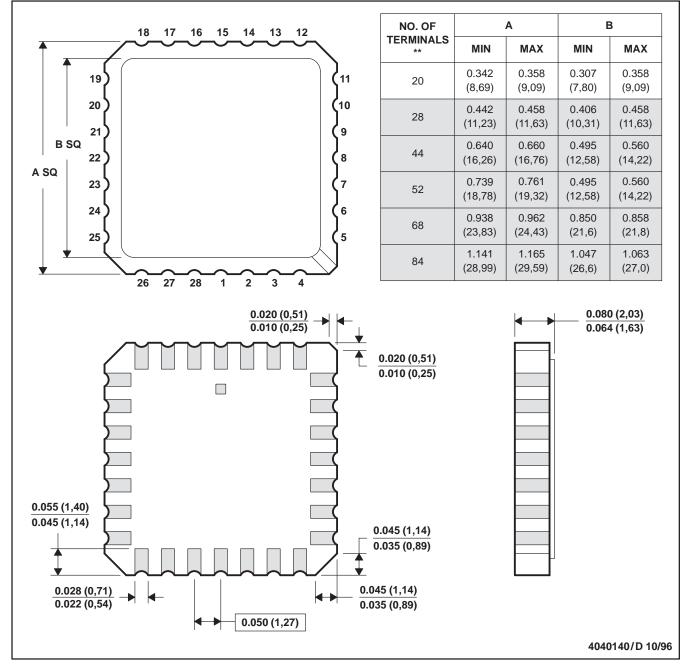
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

MECHANICAL INFORMATION

FK (S-CQCC-N**)

LEADLESS CERAMIC CHIP CARRIER

28 TERMINAL SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a metal lid.
- D. The terminals are gold plated.
- E. Falls within JEDEC MS-004

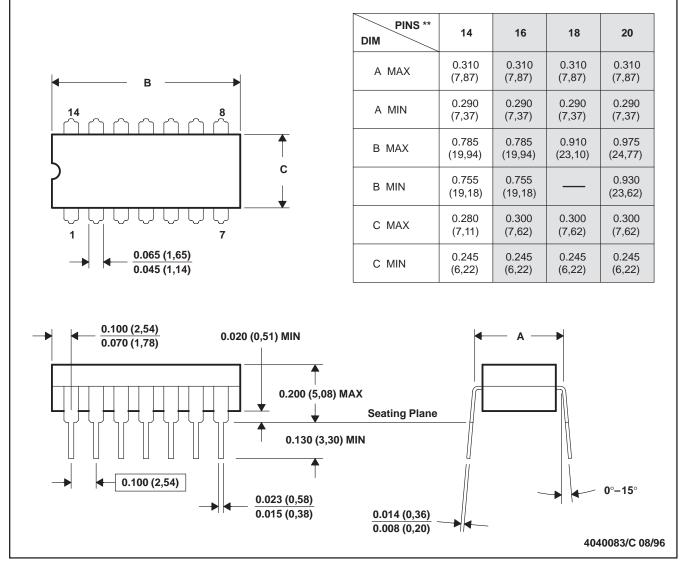


SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

MECHANICAL INFORMATION

CERAMIC DUAL-IN-LINE PACKAGE

J (R-GDIP-T**) 14 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL-STD-1835 GDIP1-T14, GDIP1-T16, GDIP1-T18, and GDIP1-T20



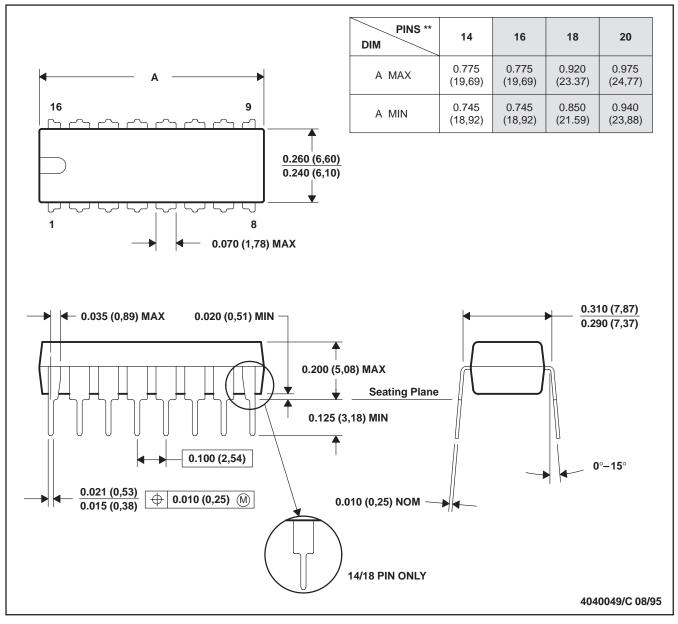
SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

MECHANICAL INFORMATION

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-001 (20 pin package is shorter then MS-001.)

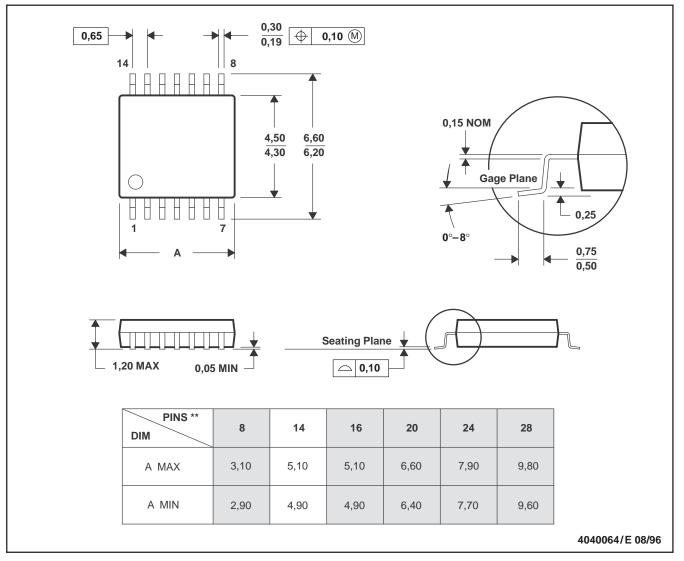


SLOS092C - SEPTEMBER 1987 - REVISED MARCH 1998

MECHANICAL INFORMATION

PLASTIC SMALL-OUTLINE PACKAGE





NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1999, Texas Instruments Incorporated